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Application/Control No.	Applicant(s)/Patent under Reexamination
10/658,392	HIRANO ET AL.
Examiner	Art Unit
Kiet T. Nguyen	2881

SEARCHED			
Class	Subclass	Date	Examiner
250	282 281 288	4/18/2006	KN
	<i>.</i>		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	1		

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY))
	DATE	EXMR
EAST including Interference Searched	4/18/2006	KN
		